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Titles

ISO: IEEE J. Sel. Top. Appl. Earth Observ. Remote Sens.
JCR Abbrev: IEEE J-STARS

Categories

ENGINEERING, ELECTRICAL & ELECTRONIC - SCIE;
GEOGRAPHY, PHYSICAL - SCIE;
REMOTE SENSING - SCIE;
IMAGING SCIENCE & PHOTOGRAPHIC TECHNOLOGY - SCIE;

Languages

ENGLISH

12 Issues/Year;

Key Indicators													
Year	Total Cites	Journal Impact Factor	Impact Factor Without Journal Self Cites	5 Year Impact Factor	Immediacy Index	Citable Items	Cited Half-Life	Citing Half-Life	Eigenfactor Score	Article Influence Score	% Articles in Citable Items	Normalized Eigenfactor	Average JIF Percentile
	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph	Graph
2016	5,514	2.913	2.454	3.199	0.752	496	2.8	7.7	0.01705	0.822	100.00	1.95346	72.826
2015	3,033	2.145	1.588	2.613	0.394	465	2.8	7.9	0.01093	0.707	100.00	1.24538	67.510
2014	2,331	3.026	1.966	3.303	0.515	445	2.6	8.0	0.00792	0.821	100.00	0.88725	81.744
2013	1,273	2.827	1.582	2.962	0.373	236	2.3	7.5	0.00487	0.735	100.00	0.53688	80.329
2012	771	2.874	1.874	2.815	0.857	182	1.9	6.9	0.00226	0.599	100.00	Not A...	79.898
2011	306	1.489	1.351	1.675	0.969	96	1.8	8.0	0.00126	0.572	98.96	Not A...	66.153
2010	77	1.140	1.035	1.140	0.190	63	Not A...	7.0	0.00048	0.437	100.00	Not A...	57.932
2009	18	0.692	0.384	0.692	0	23	Not A...	6.3	0.00005	0.090	100.00	Not A...	30.489

- Source Data
- Rank
- Cited Journal Data
- Citing Journal Data
- Box Plot
- Journal Relationships

Journal Source Data					
	Citable Items			Other (O)	Percentage (C/(C + O))
	Articles	Reviews	Combined (C)		
Number in JCR Year 2016 (A)	496	0	496	10	98%
Number of References (B)	19,816	0	19,816	192	99%
Ratio (B/A)	40.0	0.0	40.0	19.2	

InCites Journal Citation Reports dataset updated Jun 14, 2017